

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Akira Ishikawa Art Unit : Unknown
Serial No. : New Divisional Application Examiner : Unknown
Filed : December 3, 2003
Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Under 35 USC §120, this application relies on the earlier filing date of application serial number 09/951,384, filed on September 14, 2001. The attached list of references were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12/8/03



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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-075002	Application No. New Divisional
	Applicant Akira Ishikawa		
	Filing Date December 3, 2003	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,376,561	12/27/1994	Vu et al.			04/24/1992
	AB	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
	AC	5,757,456	05/26/1998	Yamazaki et al.			03/08/1996
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AN							
	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.